

## **IEC QUALITY ASSESSMENT SYSTEM (IECQ)**

covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

## Schedule of Scope to Certificate of Approval

## **Independent Testing Laboratory**

IECQ Certificate No.: IECQ-L ULTW 16.0003-02
CB Certificate No.: 20002490 ITL

Schedule Number: IECQ-L ULTW 16.0003-02-S Rev No.: 6 Revision Date: 2023/08/15 Page 1 of 1

## Appendix-1 (20002490 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Energy Dispersive Spectrometry of X-ray (EDS)	T-SEM-3, T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
X-Ray imaging	T-EFA-3
Emission Microscopy (EMMI)	T-EFA-3
Emission Microscopy (EMMI)-InGaAs	T-EFA-3
Optical Beam Induced Resistance Change (OBIRCH)	T-EFA-3
Scanning Acoustic Tomography (SAT)	T-EFA-3
Optical Microscope (OM)	T-OMI-3
3D Optical Microscope (3D OM)	T-LAB-3
IC Layout Imaging	T-OMI-3
Circuitry analysis	T-OMI-3
Thermal Emission Microscope (THEMOS)	T-EFA-3

